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Dual N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)		
40	0.010 at V _{GS} = 10 V	12	5.9 nC		
40	0.015 at V _{GS} = 4.5 V	10	5.8110		

D₁
D₁
D₂

 D_2

SO-8

Top View

FEATURES

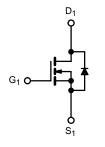
- · Halogen-free
- TrenchFET® Power MOSFET

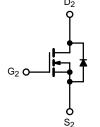


- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

- Notebook CPU Core
 - High-Side Switch





N-Channel MOSFET

N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS	3 1 _A = 28 8 , arries				
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage	V_{DS}	40	V		
Gate-Source Voltage		V_{GS}	± 20]	
	T _C = 25 °C		12		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	L	10		
Continuous Drain Current (1) = 130 C)	T _A = 25 °C	I _D	10 ^{b, c}	А	
	T _A = 70 °C		8 ^{b, c}		
Pulsed Drain Current		I _{DM}	45		
Continuous Source-Drain Diode Current	T _C = 25 °C	,	3.2		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	1.6 ^{b, c}	7	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	17		
Avalanche Energy	L = 0.1 11111	E _{AS}	21	mJ	
	T _C = 25 °C		4.1	W	
Maximum Daylar Dissipation	T _C = 70 °C	P_{D}	2.5		
Maximum Power Dissipation	T _A = 25 °C	'D	2.1 ^{b, c}		
	T _A = 70 °C		1.2 ^{b, c}		
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R_{thJA}	39	53	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	25	29	C/VV	

Notes:

- a. Base on $T_C = 25$ °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 85 °C/W.



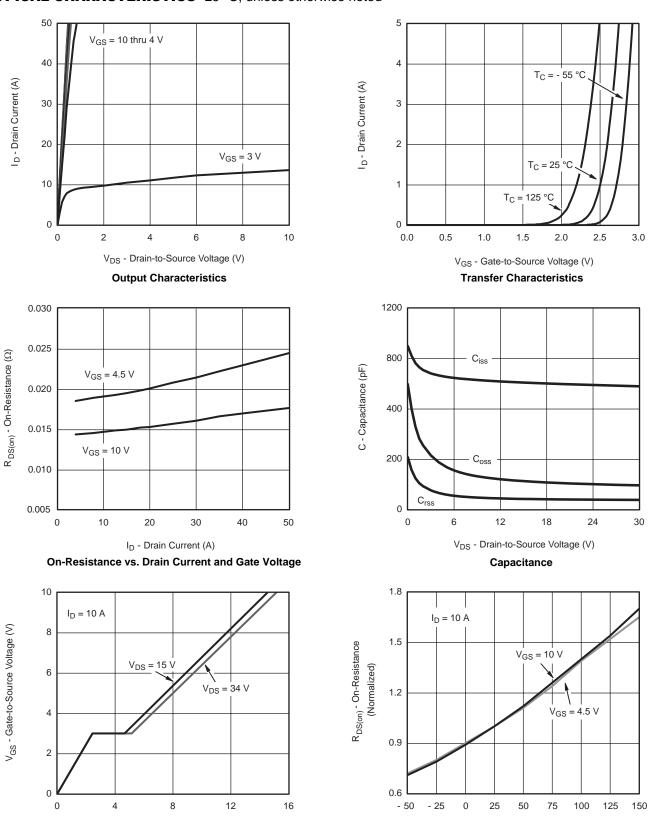
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	40			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			28		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	I _D = 250 μA		- 6			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.2		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
		V _{DS} = 40 V, V _{GS} = 0 V			1	† .	
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 40 V, V _{GS} = 0 V, T _J = 55 °C			10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			Α	
		V _{GS} = 10 V, I _D = 10 A		0.010		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 9 A		0.015			
Forward Transconductance ^a	g _{fs}	V _{DS} = 15 V, I _D = 10 A		52		S	
Dynamic ^b						1	
Input Capacitance	C _{iss}			641		pF	
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		175			
Reverse Transfer Capacitance	C _{rss}			73			
T		V _{DS} = 15 V, V _{CS} = 10 V, I _D = 10 A		15	23		
Total Gate Charge	Q_g			5.9 10.2	-		
Gate-Source Charge	Q_{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 10 \text{ A}$		2.5		nC	
Gate-Drain Charge	Q_{gd}			2.3			
Gate Resistance	R_g	f = 1 MHz	0.36	1.8	3.6	Ω	
Turn-On Delay Time	t _{d(on)}			16	24		
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.4 Ω		12	18		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 9 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		16	24		
Fall Time	t _f			10	20	1	
Turn-On Delay Time	t _{d(on)}			8	16	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.4 Ω		10	20		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 9$ A, V_{GEN} = 10 V, R_g = 1 Ω		16	24		
Fall Time	t _f			8	15		
Drain-Source Body Diode Characterist	ics			1	'	•	
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			17		
Pulse Diode Forward Current ^a	I _{SM}				45	- A	
Body Diode Voltage	V_{SD}	I _S = 9 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			15	30	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L = 0 A dl/dt = 100 A/··· T 25 ° C		6	12	nC	
Reverse Recovery Fall Time	t _a	$I_F = 9 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		8			
Reverse Recovery Rise Time	t _b			7		ns	

Notes

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





服务热线:400-655-8788

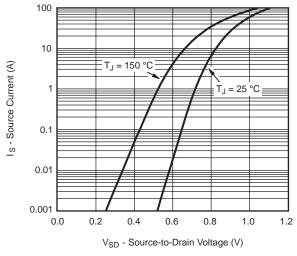
Q_q - Total Gate Charge (nC)

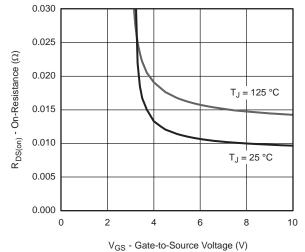
Gate Charge

T_J - Junction Temperature (°C)

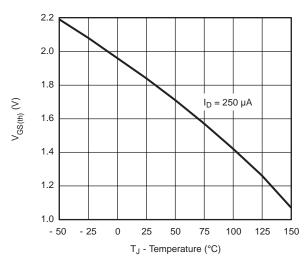
On-Resistance vs. Junction Temperature



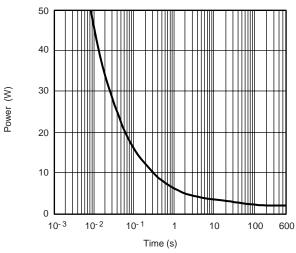




Source-Drain Diode Forward Voltage

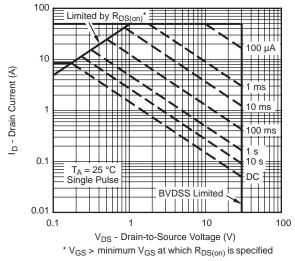


On-Resistance vs. Gate-to-Source Voltage



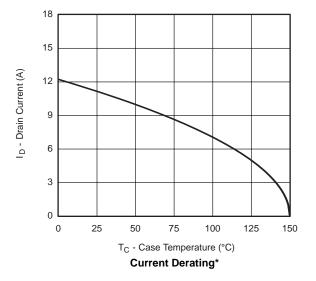
Threshold Voltage

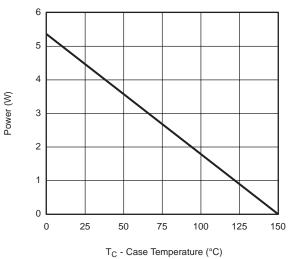


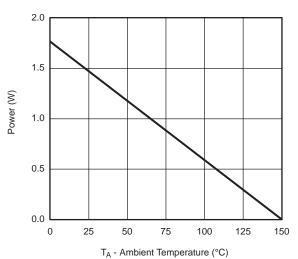


Safe Operating Area, Junction-to-Ambient







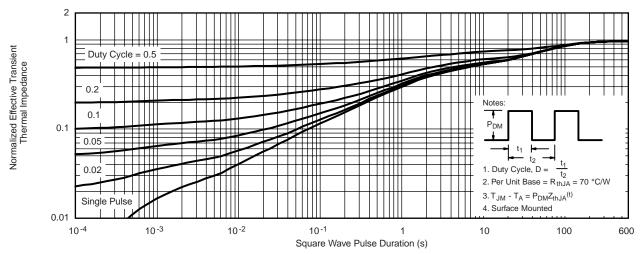


Power Derating, Junction-to-Foot

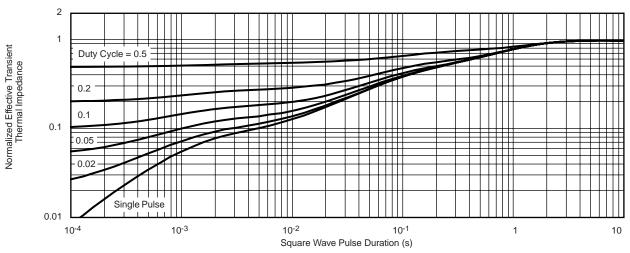
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient

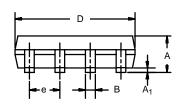


Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







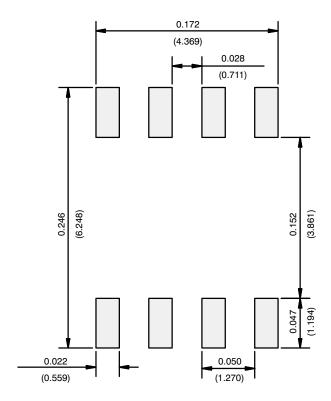
	MILLIM	IETERS	INC	HES	
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FCN: C-06527-Rev I 11-Sen-06					

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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